Picometer-Resolution MEMS Segmented Deformable Mirror NASA Phase I SBIR: NNX11CE94P

Dielectric Coating of MEMS

Deformable Mirrors

NSF Phase I SBIR: IIP-1014435

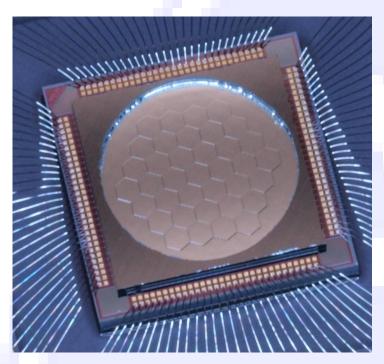
Michael A. Helmbrecht Iris AO, Inc.

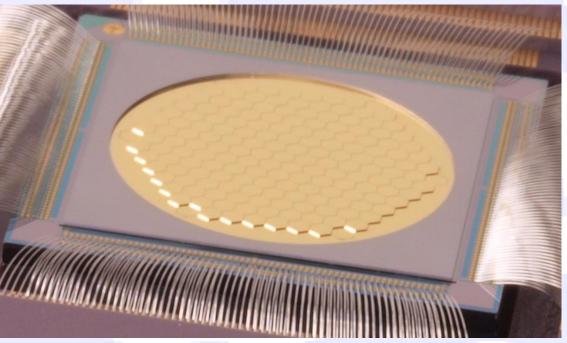
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Iris AO MEMS Segmented Deformable Mirrors





PTT111 DM

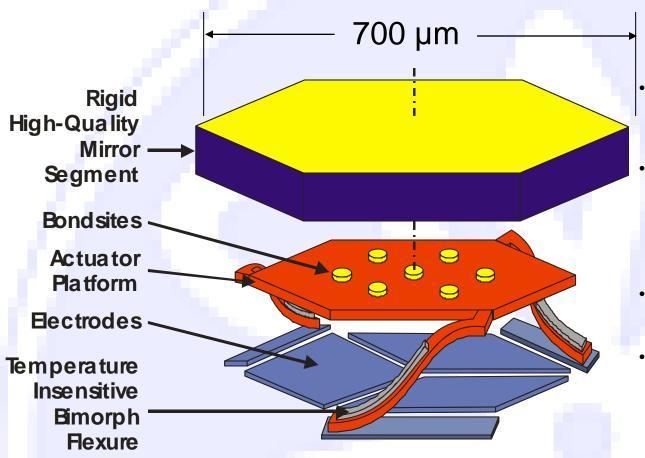
- 111 Actuators
- 37 PTT Segments
- 3.5 mm inscribed aperture
- Factory calibrated

PTT489 DM

- 489 Actuators
- 163 PTT Segments
- 7.7 mm inscribed aperture
- Factory calibrated



Iris AO Segmented DM Background



3 DOF: Piston/tip/tilt electrostatic actuation – no hysteresis

Hybrid fabrication process

- 3-poly surface micromachining
- Single-crystal-silicon assembled mirror
- Unit cell easily tiled to create large arrays

Hybrid technology

- Thick mirror segments
- Enables back-side stress-compensation coatings

Small Picometer-Resolution MEMS Segmented DM – Phase I SBIR

Business Innovation Research

Iris AO, Inc. Berkeley, CA

INNOVATION

Design and fabrication process improvements to reduce unpowered surface-figure errors from MEMS-based deformable mirrors.

TRL Assessment - Start: 3/4 End: 3/4

TECHNICAL ACCOMPLISHMENTS

- Codified systematic and random effects that contribute to un-powered mirror segment position variations of 1st generation PTT489 DM prototypes
- Modified fabrication process to reduce low-order chip bow
- Preliminary development of post-processing technique to compensate for chip-bow variations
- Modified DM segment design to make it more robust to misalignment and manufacturing tolerances

FUTURE PLANS

- Implement design and fabrication process changes on a production run of the a 489 actuator 163-piston/tip/tilt-segment deformable mirror
- ♦ Build a 939-actuator, 313-PTT segment DM

GOVERNMENT/SCIENCE APPLICATIONS

- PTT489 DM being used for the Extrasolar Planetary Imaging Coronagraph (EPIC), PI: Mark Clampin, NASA/GSFC
- PTT111 DM (111-actuator, 37-piston/tip/tilt segment) used as a hardware simulator to test co-phasing of the JWST segments
- Extend to 1000 actuator devices for high turbulence imaging and laser communication applications (DoD) and 3000 actuators for high-contrast imaging applications (NASA)
- Demonstrate control to XX nm



COMMERCIALIZATION

- Commercially Available Products:
 - PTT111 and PTT489 deformable mirrors
 - Smart Driver II: High voltage drive electronics
 - ◆ PTT111 and PTT489 AO Engine: Closed-loop adaptive optics system
- 6 patents awarded
- DMs purchased by academic and commercial researchers in vision science, ophthalmology, laser manufacturing, astronomy, and defense
- ◆ Better SWAP compared to piezoelectric stacked-actuator DMs
- No hysteresis
- Factory calibrated position controller linearizes operation and limits operation to safe bounds.
- Larger stroke than competing large-actuator technologies while maintaining speed

Iris AO, Inc. Exoplanet Imaging Requirements: VNC Technology

- **Usable Dynamic Range (Stroke):** $0.5 \mu m$
- **Segment Control Resolution: 25**

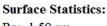
pm

- ~1000 Segment DM
- Segment Flatness: 1-3 nm rms
 - 2 nm rms demonstrated
- Robust to snap-in failures
 - **Anti-snap-in device (ASD)** technology survives 100M snap-in events



Mag: 5.5 X

Surface Data



Ra: 1.59 nm Rq: 1.98 nm Rz: 11.66 nm Rt: 12.00 nm

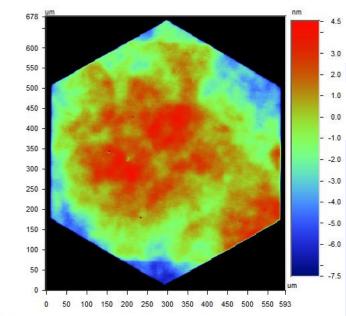
Set-up Parameters:

Size: 392 X 384 Sampling: 1.52 um

Processed Options:

Terms Removed:

Tilt Filtering: None



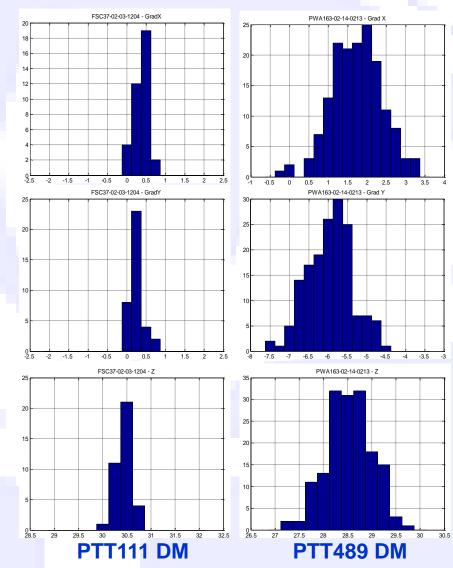
Title: FSC37-02-03-1814

Note: Segment 27



PTT489 DM Prototypes (First Silicon): *Pre-Phase I Background*

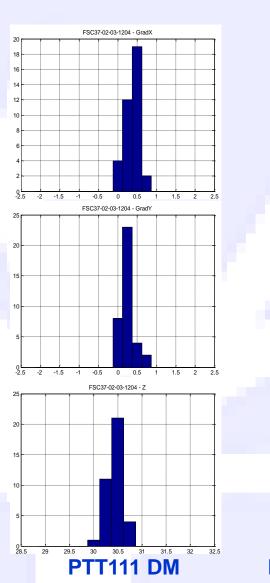
- Best DM 1 bad segment
 - > 5µm stroke
 - Too large for 25 pm resolution requirement
 - Mirror flatness: < 3 nm rms over 400 μm region
- Worst DMs: Excessive systematic segment tilts
 - Root cause misaligmnent during contact photolithography
- Relatively large random segment positions
 - Larger variations in contact photolithography compared to stepper lithography

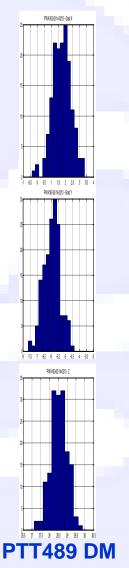




Phase I SBIR Goals

- Mitigate unpowered segment-position variations that reduce usable range
- Floor-plan design of PTT939 DM

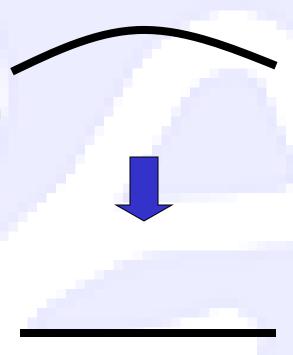






Phase I Development - Chip Bow

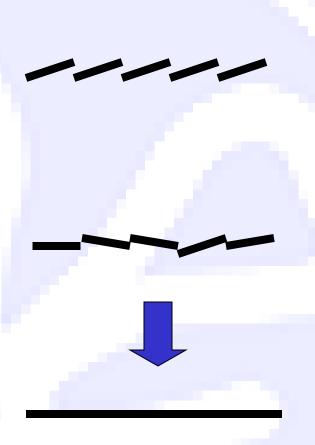
- Systematic: stresses in thin films on top of wafer
 - Layer thicknesses modified to reduce net bow
 - Modifications to be implemented in production run
- Random: run-to-run and wafer-towafer variations in thin-film stresses
 - Post-process compensation technique developed
 - Variation of curvatures should be covered





Phase I Development – Segment Position Variations

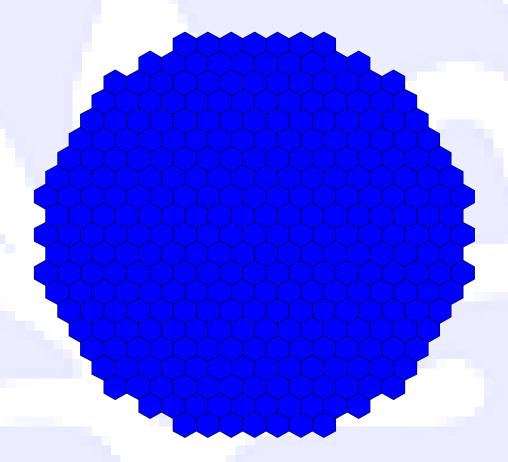
- Systematic tilts from misalignment during lithography
 - Designed self-aligned structures
- Random segment positions
 - Modified designs to make less susceptible to dimensional variations
- Short-loop run to demonstrate design modifications
- Will be implemented in production run
 - Incorporate ASD technology





PTT939 Design: *Towards* 1000 Segments

- 939 Actuators
- 313 PTT Segments
- 10.85 mm aperture





Phase II Goals

- Improve unpowered segment position errors:
 - < 200-300 nm rms
 - Analyze PTT489 production run results
 - Modify designs for lithography using DUV stepper
- Complete PTT939 design
- Fabricate PTT939 prototypes



Future Development Timeline



Small Business Innovation Research

Dielectric Coating of MEMS Deformable Mirrors

Iris AO, Inc. Berkeley, CA

INNOVATION

Design and fabrication process developments to enable use of DMs with high-power lasers. Developments enable application of highly-reflective dielectric coatings onto DMs that range from 355 nm to 1540 nm.

TRL Assessment - Start: 2/3 End: 3/4

TECHNICAL ACCOMPLISHMENTS

- Developed a compensation layer to enable dielectric coating of DMs for 1064 and 1540 nm
- Fabricated mirror arrays with compensation coatings
- ♦ Demonstrated λ/20 coatings at 532nm, 1064nm and 1540 nm
- Conducted laser testing showing ability of DMs with existing packaging to handle 150 W/cm²
- ◆ Laser testing and models show with heatsinking, 1200 W/cm²

FUTURE PLANS

- ◆ Improve DM design to enable >2000 W/cm² power handling
 - Heatsinking
 - ◆ Compensate for CTE mismatches
 - Reduce segment gaps

GOVERNMENT/SCIENCE APPLICATIONS

- ◆ Laser guidestar uplink correction
- ◆ Free-space laser communications
- ◆ Potential DoD and Directed Energy Applications
 - Designator lasers
 - Probe beams for HEL systems
 - Countermeasures for heatseaking missiles
- ◆ Extend power handling to >2000 W/cm²
- Increase DM size



COMMERCIALIZATION

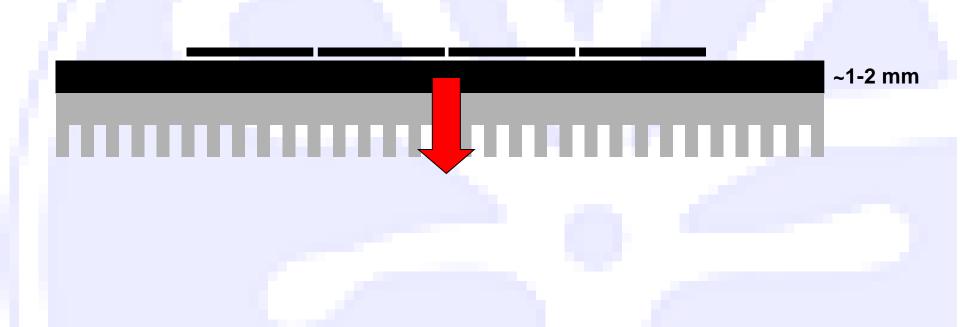
- Commercially Available Products:
 - PTT111 and PTT489 deformable mirrors
 - Smart Driver II: High voltage drive electronics
 - ◆ PTT111 and PTT489 AO Engine: Closed-loop adaptive optics system
- 6 patents awarded
- DMs purchased by academic and commercial researchers in vision science, ophthalmology, laser manufacturing, astronomy, and defense
- High-speed focus correction and beam shaping for laser micromachining
- ◆ Better SWAP compared to piezoelectric stacked-actuator DMs
- No hysteresis
- Factory calibrated position controller linearizes operation and limits operation to safe bounds.
- Larger stroke than competing large-actuator technologies while maintaining speed

Iris AO Contact
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MEMS Benefit: Short Thermal Paths

- MEMS are planar devices
 - Short thermal path to heatsinks possible

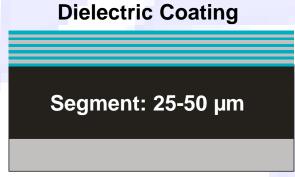




Dielectric Coatings

- Damage thresholds: >100X of metal coatings
- Coating thickness: ~5x λ
- Coating temperature: 300-400 °C
- Residual stress
 - Up to 100 MPa
 - Can be humidity dependent
- Thicker Segments 50 μm
- Stress compensation layer
- 1st demonstration of customized DM for dielectrics
 - >99.9% reflectance dielectric coatings @ 532 nm
 - < 30 nm rms residual surface figure errors</p>
 - ~2.6 µm thick coating
 - PV deformation: ~1nm/°C





Stress Compensation Coating



Phase I Goals

- Demonstrate stress-compensation for 1064 nm and 1540 nm coatings
 - Figure errors < λ/20
- Test laser-power-handling of 532 nm DM
- Develop thermal models



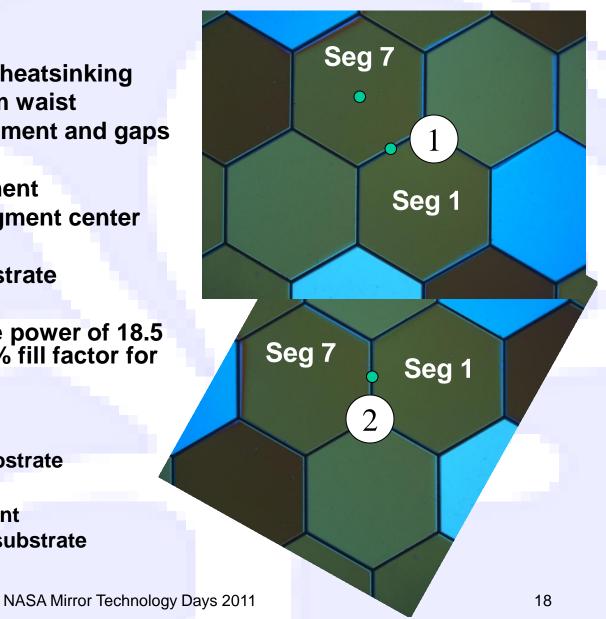
Phase I Coatings: 1064 and 1540nm

- Stress testing of 1064 and 1540 nm coatings
- Compensation layer design
- Mirror-wafer fabrication with compensation layer
- DM array fabrication and coating
- 1064 nm
 - **>99.85%**
 - Coating thickness: 5.4 µm
 - Segment figure errors: <λ/20
- 1540 nm
 - **>99.85%**
 - Coating thickness: 7.9 µm
 - Segment figure errors: <λ/20



532 nm Laser Testing

- Standard packaging no heatsinking
- 2W Gaussian beam, 25 µm waist
- 155 min CW onto DM segment and gaps
 - >200 kW/cm² in beam
 - 630 W/cm² onto segment
- Heating from 2W onto segment center
 - 14.6 °C from ambient
 - 8.7 °C above DM substrate
- 0.74W into the gap
 - Equivalent to average power of 18.5
 W onto segment (96% fill factor for this DM)
 - 1. Upper Image
 - 9.8 °C from ambient
 - 6.1 °C above DM substrate
 - 2. Lower Image
 - 146.4 °C from ambient
 - 134.8 °C above DM substrate





Thermal Model Projections (532nm tests)

- Assumptions
 - Limit deformations from heating to <λ/40 (13.3 nm rms)
 - Assume linear superposition
- Power handling of PTT111 DM
 - Existing packaging
 - 150 W/cm²
 - 14 W onto PTT111 DM
 - Good heatsink case (Phase II)
 - 1200 W/cm²
 - 110 W onto PTT111 DM



Phase II Goals

- Improve power handling capabilities: 1-2 kW/cm²
 - Compensate for stress and CTE mismatches in the coatings
 - Increase fill factor to >98%
 - Packaging for lasers heatsinking
- Improve mirror figure: <λ/40
- Speed improvements
 - Regain speed loses from using thicker 50 µm segments



Future Development Timeline





Summary

- Lower unpowered segment position errors
 - < 200-300 nm rms</p>
- Larger DM arrays
 - 10³ actuators
- Improved laser power handling
 - 1-2 kW/cm²
 - Changes in segment figure from laser heating
 <λ/40